



Lattice Nexus 2 SED/SEC User Guide

Preliminary Technical Note

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This document was created consistent with Lattice Semiconductor's inclusive language policy. In some cases, the language in underlying tools and other items may not yet have been updated. Please refer to Lattice's inclusive language [FAQ 6878](#) for a cross reference of terms. Note in some cases such as register names and state names it has been necessary to continue to utilize older terminology for compatibility.

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Abbreviations in This Document

A list of abbreviations used in this document.

Abbreviation	Definition
ASCII	American Standard Code for Information Interchange
CRC	Cyclic Redundancy Check
CRAM	Configuration Random Access Memory
DSP	Digital Signal Processing
DSR	Data Shift Register
EBR	Embedded Block RAM
ECC	Error Correction Code
ID	Identification
IP	Intellectual Property
PFU	Programmable Function Unit
PLD	Programmable Logic Device
SEC	Soft Error Correction
SED	Soft Error Detection
SEDC	Soft Error Detection/Correction
SEI	Soft Error Injection
SEU	Single Event Upset
SRAM	Static Random Access Memory

1. Introduction

This document describes the hard-logic soft error detection (SED) and soft error correction (SEC) implemented in the Lattice Nexus™ 2 device platform. When a soft error is detected, the Nexus 2 devices provide an easy way to optionally perform SEC without affecting the functionality of the device.

Memory errors can occur when high-energy charged particles alter the stored charge in a memory cell in an electronic circuit. The phenomenon first became an issue in Configuration Random Access Memory (CRAM), requiring error detection and correction for large memory systems in high-reliability applications. As device geometries continue to shrink, the probability of memory errors in Static Random Access Memory (SRAM) becomes significant for some systems.

SRAM-based programmable logic devices (PLDs) store logic configuration data in SRAM cells. As the number and density of SRAM cells in a PLD increase, the probability that a memory error alters the programmed logical behavior of the system increases. Most traditional approaches that are taken to address this issue involve soft intellectual property (IP) cores that you instantiate in your design. Such approaches utilize valuable resources, possibly affecting design performance.

The Nexus 2 devices have an improved hardware-implemented SEDC circuit that can be used to detect and correct SRAM errors. There are two layers of SED/SEC, error correction code (ECC) logic to detect and correct single bit error per data frame and detect two-bit errors and cyclic redundancy check (CRC) logic to detect multi-bit errors in the device.

2. Overview of the SEDC IP

The Soft Error Detection/Correction (SEDC) IP offers the following enhanced features:

- Frame-by-frame SED check
- Multiple regions run in parallel for fast SED and SEC performance
- Single-bit and multi-bit error detection
- ECC to correct single bit error at the frame level
- Programmable SEDC clock
- Force error capability for system-level simulation

The SEDC module is part of the sysCONFIG block in the Nexus 2 devices. The configuration data is divided into frames in multiple regions. The SED hardware reads data from the FPGA's configuration memory frame-by-frame in the background while the device is in user function mode and performs ECC calculation on every frame of configuration data (see Figure 2.1). When a single-bit error is detected, a single event upset (SEU) notification is generated and the SED resumes operation after the single-bit error is corrected. Single-bit errors are corrected when SEC is enabled. The corrected value is rewritten to the frame using ECC information. If more than one bit errors are detected within one frame of configuration data, an error message is generated. In parallel, CRC is calculated for the entire CRAM contents along with ECC. After the ECC is calculated on all frames of configuration data, CRC is calculated for the configuration data in the entire device. Full-chip CRC and frame-by-frame ECC calculations do not include Embedded Block RAM (EBR). EBRs provide a separate and optional ECC for SED/SEC of the EBR content. Distributed RAM data stored in the CRAM are masked during SED/SEC because RAM content may change during user operation and hence cannot be covered by the SEDC IP without generating false SEDC errors. The distributed RAM enable bit set in CRAM is covered during SED/SEC.

The SEDC IP is part of the sysCONFIG block in the Nexus 2 devices. Figure 2.1 shows the system-level view of the SEDC IP.

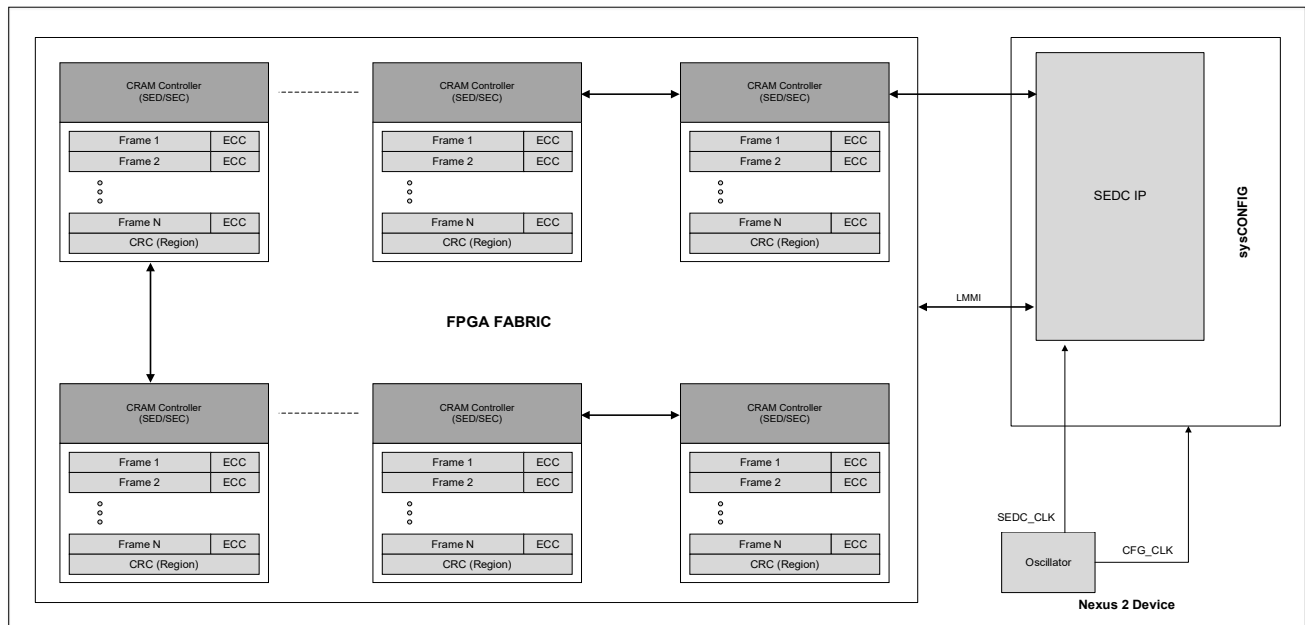


Figure 2.1. SEDC System Block Diagram

2.1. SEDC IP Clock and Reset

The SEDC circuitry is driven by the FPGA's internal oscillator.

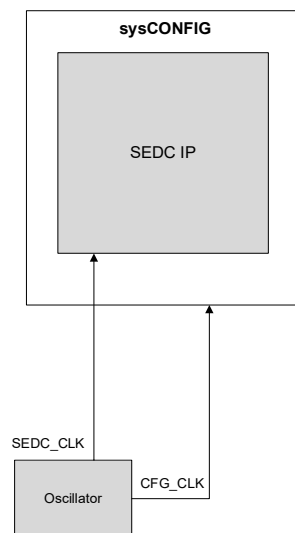


Figure 2.2. SEDC IP Clock and Reset

The default oscillator frequency is 200 MHz. You can set the SEDCLK_divider setting in the SEDC IP from the Lattice Radiant™ software IP catalog anywhere between 2 to 256 in integer increments resulting in a frequency range from 200 MHz to 1.56 MHz (SEDC oscillator frequency = 400 MHz / SEDCLK_divider).

Table 2.1. SEDC Internal Oscillator Divider Settings

Divider Setting	SEDCLK_Divider	SEDC Clock Frequency (MHz)
Divide by 2	2	200
Divide by 3	3	133.33
...	...	...
Divide by 256	256	1.56

3. SEDC Flow

This section describes the SEDC flow. The SEDC flow is executed once V_{CC} reaches the data sheet V_{CC} minimum recommended level and SEDC is started.

The Nexus 2 devices have an advanced SEDC flow with two levels of SEDC checks. In the first level of SED check, the CRAM content is read one frame at a time and the SED check is performed on a frame-by-frame basis. After all the frames of the device CRAM content are read, the SEDC module performs a CRC of the entire CRAM contents (second-level SED) to check for any multi-bit errors which were not detected by ECC.

The Nexus 2 devices are built to support real-time SEC in which a single-bit soft error can be corrected using ECC at the frame level. A multi-bit soft error detected within a frame is non-correctable. [Figure 3.1](#) shows the SEC flow in the Nexus 2 devices.

The Nexus 2 devices perform a one-time scan of all frames and can detect single-bit (1 bit) and multi-bit (2 bits or more) soft errors. When a single-bit soft error is detected, the hardware halts, notifies the user about the error, and waits for the instruction to proceed. Once the instruction to resume scanning is set, the hardware corrects the 1-bit error, rescans the region where the corrected frame is located, and resumes scanning the remaining frames. When a multi-bit soft error is detected, the hardware notifies the user about the error and continues scanning the remaining frames because a multi-bit soft error is non-correctable.

The following are the bit error reporting schemes:

- When a single-bit soft error is detected, the SEDC IP reports the following:
 - An error indicator with error type of 1-bit error
 - Error bit location
 - Error frame location
 - Error region location
- When a multi-bit soft error is detected, the SEDC IP reports the following:
 - An error indicator with error type of multi-bit (uncorrectable) error
 - Error frame location
 - Error region location
- After a complete scan of the CRAM content, if any soft error was detected, the SEDC IP reports the following:
 - An error indicator with error type of full-chip CRC

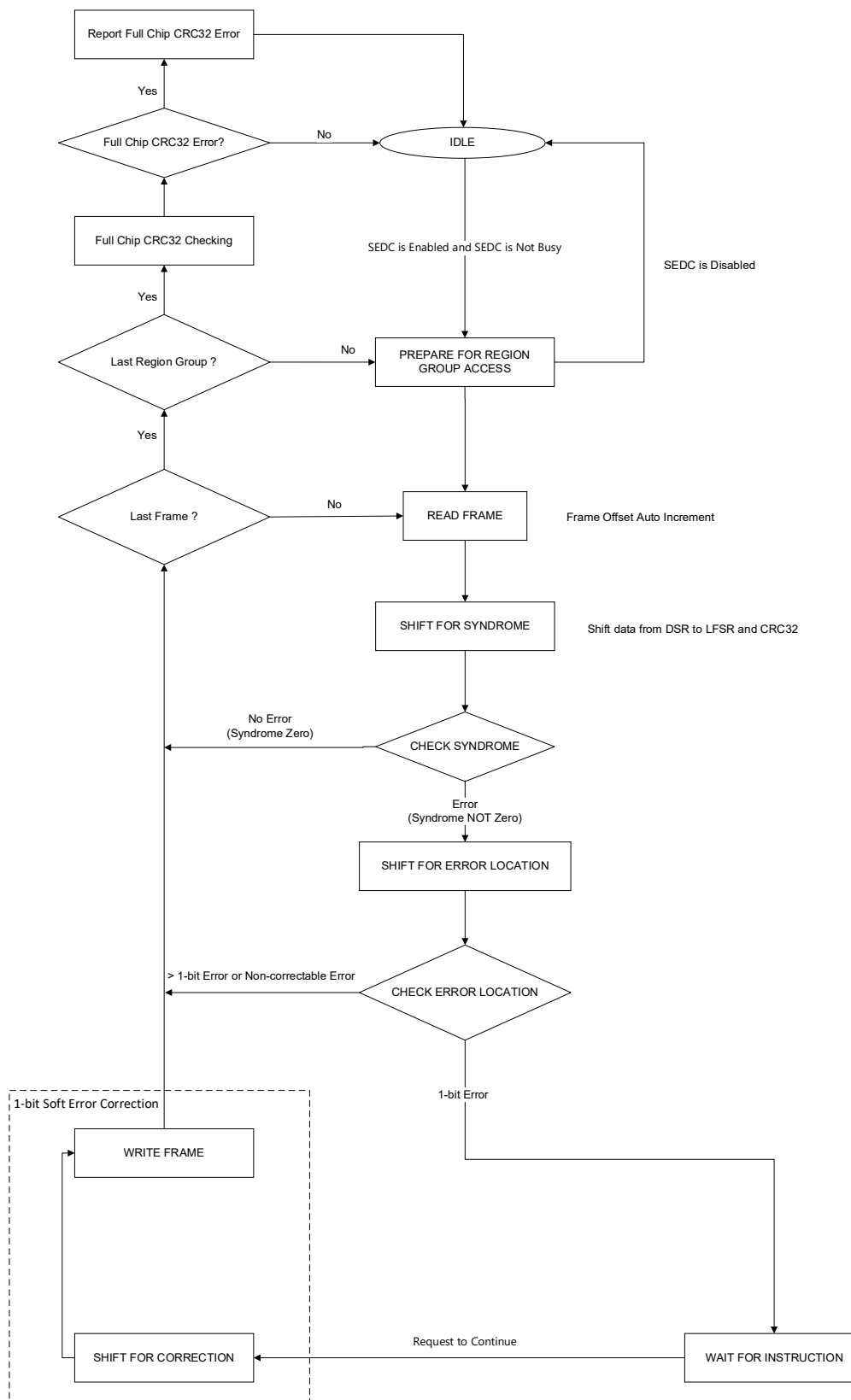


Figure 3.1. SEDC Flow

4. SEDC Run Time

In Nexus 2 devices, the SED run time required to complete a SED check depends on the data shift register (DSR) length, the SED clock period, the number of configuration frames and regions being scanned, and the additional calculation overhead. As device density increases, the number of configuration frames and regions also increases, resulting in longer SED run times. Because the run time is directly proportional to the SED clock period, using a higher SEDC clock frequency (shorter clock period) reduces the overall SED check time. Use the following formula to approximate the SED run time:

$$\text{SED Run Time (ms)} = (34 + \text{DSR Length per Frame}/16 + 1) \times \text{SEDC Clock Period} \times \text{Configuration Frame per Region} \times (\text{Configuration Region}/4) + 3.46 \text{ ms}$$

Example:

For LN2-CT-20 device with SEDC_CLK = 200 MHz (Clock Divider = 2):

$$\text{SEDC Run Time} = (34 + 560/16 + 1) \times 0.000005 \text{ ms} \times 7526 \times (10/4) + 3.46 \text{ ms} = 10.04 \text{ ms}$$

The following table shows the configuration-related parameters that affect SED run time.

Table 4.1. Configuration-related Parameters that Affect SED Run Time

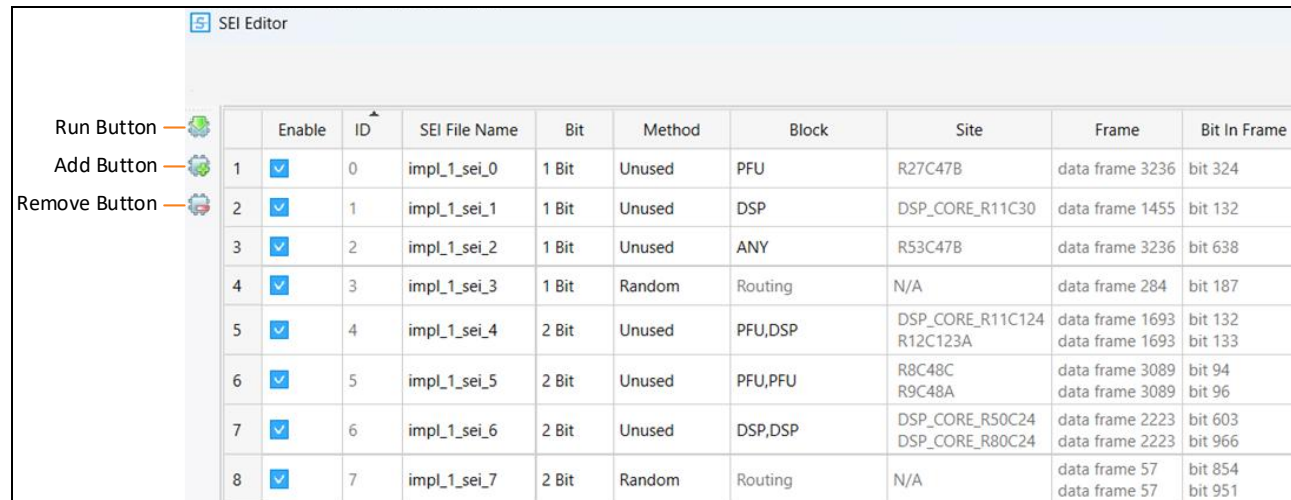
Device	Configuration Frame per Region	Configuration Region	DSR Length per Frame
LN2-CT-20	7526	10	560
LN2-MH-20	7526	10	560

5. Soft Error Injection

The Radiant soft error injection (SEI) tool offers an easy and economical way to emulate soft error impact on the overall system. This tool allows you to randomly generate and program one or multiple soft errors into the device in background mode without affecting device function. The Radiant SEI tool is supported in the Lattice Radiant software version 24.2.1 and higher.

To use the Radiant SEI tool:

1. Select **Tools > SEI Editor**. The SEI editor appears as shown in [Figure 5.1](#). The SEI editor allows you to create a special one-frame bitstream that differs from the original bitstream by one bit or two bits.



	Enable	ID	SEI File Name	Bit	Method	Block	Site	Frame	Bit In Frame
1	☒	0	impl_1_sei_0	1 Bit	Unused	PFU	R27C47B	data frame 3236	bit 324
2	☒	1	impl_1_sei_1	1 Bit	Unused	DSP	DSP_CORE_R11C30	data frame 1455	bit 132
3	☒	2	impl_1_sei_2	1 Bit	Unused	ANY	R53C47B	data frame 3236	bit 638
4	☒	3	impl_1_sei_3	1 Bit	Random	Routing	N/A	data frame 284	bit 187
5	☒	4	impl_1_sei_4	2 Bit	Unused	PFU,DSP	DSP_CORE_R11C124 R12C123A	data frame 1693 data frame 1693	bit 132 bit 133
6	☒	5	impl_1_sei_5	2 Bit	Unused	PFU,PFU	R8C48C R9C48A	data frame 3089 data frame 3089	bit 94 bit 96
7	☒	6	impl_1_sei_6	2 Bit	Unused	DSP,DSP	DSP_CORE_R50C24 DSP_CORE_R80C24	data frame 2223 data frame 2223	bit 603 bit 966
8	☒	7	impl_1_sei_7	2 Bit	Random	Routing	N/A	data frame 57 data frame 57	bit 854 bit 951

Figure 5.1. SEI Editor

Main features of the SEI editor are as follows:

- **Add** button – Click to add SEI files.
- **Remove** button – Click to remove SEI files.
- **Run** button – Click to generate SEI files. Note that this generates a data frame with flipped random bits, producing a partial bitstream output in binary bit or ASCII raw bit file format.
- **Enable** – Check the checkbox to select the specific bitstream to be generated when you click the **Run** button. Note that the generated bitstream is either a binary bit file or ASCII raw bit file. The bitstream output format setting in Radiant determines the file format. The default file format is binary bit file.
- **ID** – Continuous error ID number assigned by the software. This value is read-only.
- **SEI File Name** – Default filename for the generated bitstream. You may change the filename as desired.
- **Bit**
 - 1 Bit – Error injection of one bit within one data frame
 - 2 Bit – Error injection of two bits within one data frame
- **Method**
 - Unused – Error bit introduced into an unused block which does not affect the customer design logic.
 - Random – Error bit introduced into a random block which might or might not affect the customer design logic.
- **Block**
 - If **Bit** is set to 1 Bit and **Method** is set to Unused, **Block** can be selected as PFU, DSP, or ANY.
 - If **Bit** set to 2 Bit and **Method** is set to Unused, **Block** can be selected as one of the following options:
 - PFU, DSP
 - PFU, PFU
 - DSP, DSP

- If **Method** is set to Random, any functional block can be used including routing. However, you cannot make this selection. **Block** is read-only when **Method** is Random.
- **Site** — The exact site of the inserted error. Errors inserted into a routing block or unclassified block do not have a site. This field is read-only.
- **Frame** — The data frame of the inserted error. This field is read-only.
- **Bit in Frame** — Displays the address of the SEI frame or the bit location in the frame. This field is read-only.

Notes:

- Grey text in the **Block**, **Site**, **Frame**, or **Bit in Frame** fields indicates read-only. You cannot modify the value.
 - Once SEI bitstream generation is complete, the **Site**, **Frame**, and **Bit in Frame** fields display the site name, data frame number, and bit number, respectively, where the soft error is injected.
 - There is no site location when SEI is in a routing or unclassified block.
2. To program the SEI bitstream, select the **SEI Fast Program** operation in the Radiant Programmer.

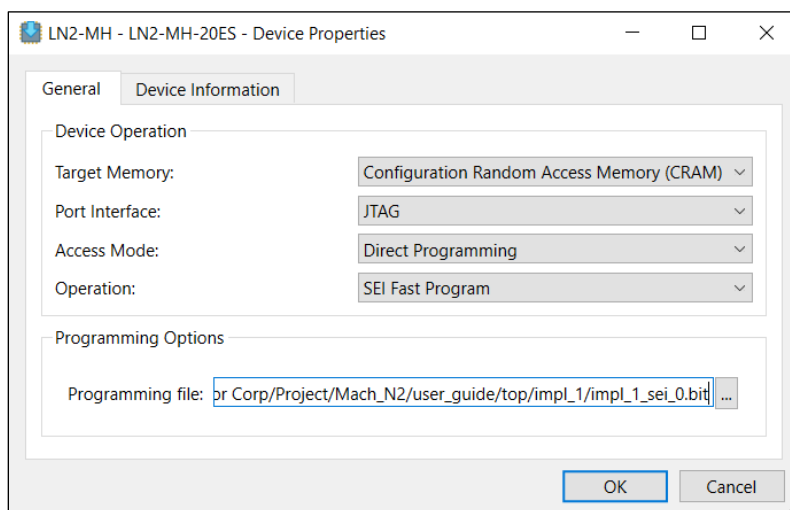


Figure 5.2. Device Properties

3. Once the SEI bitstream is programmed into the device, you can use the general SED routine to detect the soft error.
- Note:** While programming the device with the SEI bitstream, SED checking must stop. You can de-assert `sedc_run_i` of the SEDC Controller IP.

6. Important Note

SEDC operation will be interrupted once any PROG_QUALIFY target configuration command is clocked into the device. It is recommended that the SEDC operation be stopped before sending a PROG_QUALIFY target configuration command and restarted after the command is completed.

References

- [Certus-N2](#) web page
- [Mach-N2](#) web page
- [Lattice Radiant Software](#) web page
- [Lattice Insights](#) web page for Lattice Semiconductor training courses and learning plans

Technical Support Assistance

Submit a technical support case through www.latticesemi.com/techsupport.

For frequently asked questions, refer to the Lattice Answer Database at www.latticesemi.com/Support/AnswerDatabase.

Revision History

Revision 0.81, September 2026

Section	Change Summary
Abbreviations in This Document	Added <i>ASCII</i> , <i>DSP</i> , <i>DSR</i> , <i>ID</i> , and <i>PFU</i> .
SEDC Run Time	Added new section.
Soft Error Injection	Updated Radiant SEI tool support information and added steps to use the SEI tool.
References	Added Mach-N2 web page.

Revision 0.80, December 2024

Section	Change Summary
All	Initial preliminary release.



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